Consequences of Deuterium Retention and Release from Be-containing Mixed Materials for ITER Tritium Inventory Control

K. Sugiyama*, J. Roth, A. Anghel, C. Porosnicu, M. Baldwin, R. Doerner, K. Krieger, C.P. Lungu

*Max-Planck-Institut für Plasmaphysik, EURATOM Association, D-85748 Garching, Germany
National Institute for Laser, Plasma and Radiation Physics of Romania, Association EURATOM-MEdC, 077125 Bucharest, Romania
Center for Energy Research, University of California at San Diego, La Jolla, CA 92093-0417, USA

Abstract

In order to assess the tritium removal procedure currently suggested for ITER (wall baking at 513 K (240 °C) for the main chamber, at 623 K (350 °C) for the divertor), deuterium (D) retention and release behaviour of beryllium (Be) containing materials are investigated. In pure Be, D is predominantly released around 470 K with a relatively sharp desorption peak. Mixing of tungsten (W) or carbon (C) into Be changes the D desorption behaviour causing less efficiency D removal by the baking procedure. Especially, high C concentrations in Be affect the D release behaviour significantly and prevents removal of the retained D by baking at 623 K. As a consequence, the baking operation in ITER would work for tritium removal from the first wall and Be-rich deposited layers formed at low temperature areas, while it does not work for C-rich codeposited layers and/or plasma-facing surfaces heated above 623 K during a discharge.

PSI-19 Keywords: Deuterium retention, Beryllium, Carbide, Tungsten alloy
JNM keywords: B0100, C0100, D0500, F0400, H0400, P0500
PACS. No. 52.40.Hf (Plasma-wall interactions; boundary layer effects; plasma sheaths)

*Corresponding author:
Kazuyoshi Sugiyama
Max-Planck-Institut für Plasmaphysik, EURATOM Association
Boltzmannstrasse 2, D-85748 Garching, Germany
TEL: +49-(0)89-3299-1492
FAX: +49-(0)89-3299-1212
E-mail: kazuyoshi.sugiyama@ipp.mpg.de
1. Introduction

Since the current design of ITER plasma-facing components consists of different armour materials depending on the operational requirements - i.e. beryllium (Be) for the first wall material, tungsten (W) as divertor armour and carbon fibre composite for the area around the strike points [1] -, interaction of those wall materials with the plasma obviously leads to the formation of mixed material layers as seen in some of current machines - for example, in JET [2,3]. Material mixing can change fuel retention properties of the plasma-facing wall as well as its thermo-mechanical properties, which influences the hydrogen recycling on the plasma-facing surface and the tritium inventory in the vacuum vessel. In ITER, for safety reasons, periodic tritium removal will be required before the in-vessel tritium inventory reaches its administrative limit [4], meaning that control of tritium inventory strongly affects the ITER operation program after the launch of Deuterium-Tritium burning phase.

We need, therefore, to develop some reasonable tritium removal methodologies in parallel with reliable estimation of in-vessel tritium inventory buildup. A wall baking procedure with technically accessible temperatures, at 513 K (240°C) for the main chamber and 623 K (350°C) for the divertor, is currently accepted as baseline as a tritium removal operation in ITER [5]. In order to assess the efficiency of tritium removal by such wall baking, it is necessary to know the hydrogen release behaviour from not only the pure materials but also mixed materials, especially, Be-related mixed materials because Be forms the majority of the ITER plasma-facing material (~ 690 m², i.e. ~ 80 % of plasma-facing area). In this study, from these viewpoints, the thermal deuterium release behaviour from Be-containing mixed materials was investigated under controlled laboratory conditions, and the efficiency of the baking procedure is discussed for the conditions in ITER.
2. Experimental procedure

2.1 Sample preparation

Be-containing mixed samples with two different concepts were prepared. The first concept is the compound layers of Be with W or C, the second is preparation of mixed layer by means of simultaneous deposition of Be with W or C.

Compound layers were fabricated by thermally treating the different material combinations of film-substrate samples. The detailed procedure is as follows: The surface of polycrystalline Be with 99.4 % purity (provided by Goodfellow Co. Ltd.) was covered by C or W film produced by magnetron sputter deposition with the thickness of 200-300 nm. After film deposition, samples were annealed at a certain temperature and duration (773K / 3hrs for C on Be sample, 1073 K / 10 hrs for W on Be sample) under a pressure of ~10^{-8} mbar based on previous studies [6,7]. The resulting samples stoichiometrically showed the formation of Be_{2}C with ~ 900 nm thickness in the case of C on Be system and Be_{12}W with ~ 2 \mu m in the case of W on Be system, which was confirmed by Rutherford Backscattering Spectroscopy (RBS). The details of these procedures are summarized in ref. [8].

Beryllium-related depositions were done by means of Thermionic Vacuum Arc (TVA) deposition method [9] in MEdC. TVA setup has been upgraded recently allowing simultaneous Be-W or Be-C deposition using different target anodes, and succeeded in fabricating Be-W or Be-C layers with varying the Be/W or Be/C ratios [10,11]. Note that no thermal treatment was done for those Be/W or Be/C simultaneous deposited layers. Each prepared layer was also subsequently analyzed by RBS to check its thickness and composition.

2.2 Deuterium ion implantation and post mortem analysis

Deuterium (D) implantation into the prepared samples was performed in the High Current Ion Source at IPP-Garching. The energy of the D ion beam was 600 eV D_{3}^{+} (200 eV/D), which
is a characteristic value derived from typical boundary plasma temperatures including sheath acceleration. The implantation fluences were up to $\sim 4 \times 10^{23} \text{ D/m}^2$ with a flux of $\sim 3 \times 10^{19} \text{ D/m}^2\text{s}$ (Note that the particle fluence to the ITER first wall is expected to be order of $10^{23} /\text{m}^2$ after only single 400 s discharge). The incident angle was normal to the target surface, and the implantation temperature was varied from room temperature to 570 K.

After the implantation, the D release behaviour of each sample was measured by thermal desorption spectroscopy (TDS) in the Thermal Effusion Spectroscopy Setup (TESS) [12] in IPP-Garching except for samples using bulk Be substrates which were analyzed in the PISCES facility in the University of California at San Diego. The temperature ramp rates were very similar for both cases, i.e. $\approx 0.25 \text{ K/s}$ in TESS and $\approx 0.29 \text{ K/s}$ in PISCES. For some of these samples, TDS was done with a specific temperature ramp program, i.e. the temperature was ramped up to 623 K, and held 20 min. at 623 K, and then further ramped up to the final temperature, in order to simulate and assess the D release during the ITER wall baking scenario. The amount of D retained in the sample was also cross-checked by nuclear reaction analysis using the $\text{D}(^3\text{He}, \text{p})^4\text{He}$ nuclear reaction before TDS.

3. Results

Figure 1 shows $\text{D}_2$ desorption spectra from pure Be and Be-containing mixed layers after the implantation with a fluence of $10^{23} \text{ D/m}^2$ at room temperature. In the case of pure Be, the dominant fraction of retained D is released around 430-470 K in a rather sharp desorption peak which has been commonly observed as the predominant D desorption stage also in Be-D codeposited layers [13] and D-implanted single/polycrystalline bulk Be with the fluences above $10^{21} \text{ D/m}^2$ [14-16]. Although the trapping states of D released at this low-temperature stage are not completely understood yet, a possible explanation is that D would be trapped as unstable
amorphous Be:D state in the structurally-modified region due to the supersaturation and in cavities formed by defect aggregation in the supersaturated region [15-17]. There is also a small desorption shoulder at 500-600 K, which agrees well with the decomposition temperature of Beryllium deuteride [18]. In the case of Be₂C, the TDS spectrum shows a similar desorption peak around 420-470 K, but its intensity is lower than that of pure Be. In addition, a broad desorption feature appears in the range from 650 to 900 K. Such D desorption pattern in the high-temperature range is always observed in D ion implanted carbon materials. Spectroscopic studies have suggested that hydrogen release in the range from 600 to 1000 K is due to the decomposition of $sp^3$-CH group [19,20]. This result implies that D implanted into Be₂C was eventually retained with either Be-related trapping (mostly released below 500 K) or C-D bond formation (released above 600 K). D desorption pattern of Be₁₂W has also the primary peak starting from around 430K. However, it shows a qualitative change, i.e. its intensity is much lower and the peak itself becomes broader compared to the case of pure Be. The discontinuous profile at 623 K seen in Be and Be₂C samples is due to the 20 min. hold at this temperature. Figure 2 shows the TD spectra of these samples as a function of operational time. The desorption flux exponentially drops down (with a time constant of roughly 125 s) after the stop of temperature ramp, and it reaches the background level within about 400 s. The amount of released D during the 20 min. hold is only 5-10 % of initially retained.

Figure 1 (b) and (c) show D desorption behaviour from Be-W and Be-C layers deposited simultaneously. One can discern that the D desorption behaviour obviously changes due to the mixing of W or C into Be. Already a 10 at. % fraction of W in Be broadens substantially the primary release peak. With an increase of the W concentration up to $\approx 60$ at. %, this peak broadens further, while the retained amount becomes much less. The influence of C in Be on D release behaviour is even more significant. While $\approx 8$ at. % of C still does not bring considerable change, in the case of C concentration of 50 at.%, the desorption peak in the low
temperature stage totally disappears, and the desorption above 550 K becomes dominant. This result indicates that D in C-rich Be-C mixed layer is predominantly trapped in C-related trapping sites. More detail about D retention in Be-W and Be-C simultaneous deposited layers is available in these proceedings [10,11].

D release behaviour from Be layers after the implantation at different temperatures is summarized in Fig.1 (d). By increasing the implantation temperature up to 423 K, the primary peak in the low temperature stage decreases significantly while the minor peak at 500-600K slightly increases. At the implantation temperature of 573 K, D release up to 520 K is suppressed while it shows pronounced D desorption around 700-800K. It can be assumed that an increase of the implantation temperature sets off chemical surface modifications, which can enhance the D trapping as the hydride or hydroxide phase.

4. Discussion

Fig. 3 shows the remaining fraction of initially retained D in each sample as a function of desorption temperature, which is derived from TDS results. Because of the dominant desorption peak already at low temperatures, the remaining fractions start dropping at temperatures around 420 K. Roughly 90 % of initially retained D is released at 623 K in the case of pure Be whereas the desorption efficiency decreases by mixing of W or C into Be. Especially, as mentioned in the previous section, almost no D is released from C-rich Be-C deposited layer (C/Be ≈ 1) until temperatures of 650 K. For implantation temperatures higher than desorption temperatures no retention of D can be expected. Therefore, D retained during implantation at a temperature of 573 K starts being released only at 623 K as shown in Fig. 3 (c).

Based on the results given above, the performance expected for the ITER wall baking
scenario can be discussed as follows:

- Best performance of the wall baking would be expected for tritium removal from high purity Be layers deposited on the main chamber wall -under the assumption that the temperature of main chamber wall surface is not so high (expected to be ~ 430 K)-.

- The efficiency of tritium removal will be limited for compounds and Be-W / Be-C simultaneously deposited layers as summarized in Fig 4. Especially, mixing of C into Be results in a significant change of hydrogen desorption behaviour. In the case of C-rich Be-C deposition, tritium it is difficult to remove by a baking at 623 K even though the deposition is formed under low temperature condition. For such case, we have to consider the application of other removal methods like laser / flash heating, oxygen discharge etc.

- It is clear tritium cannot be removed from plasma-facing surfaces where the temperature rises above 623 K during a discharge. Even for an implantation temperature of 423 K, only about 50 % is released at 623 K. On the other hand, it can be expected that the amount of primary tritium retention decreases with the surface temperature rise as shown in ref. [21].

5. Conclusion

In order to assess the tritium removal operation currently suggested for ITER, (wall baking at 513 K (240 °C) for the main chamber, at 623 K (350 °C) for the divertor), deuterium (D) retention and release behaviour of Beryllium (Be)-containing materials are investigated.

In pure Be, D is predominantly released around 420-470 K within relatively sharp desorption peak. Mixing of tungsten (W) or carbon (C) in Be changes the D release behaviour resulting in less efficient D removal by the baking procedure. Especially, C concentration in Be
affects D release behaviour significantly and makes it difficult to remove the retained D by baking at 623 K. As a consequence, the baking operation in ITER would work for tritium removal from the first wall and Be-rich deposited layers formed at low temperature areas (< 423 K), while it does not work efficiently for C-rich codeposited layers or the plasma-facing surface heated above 623 K during a discharge.

Acknowledgement

The authors appreciate J. Dorner, Th. Dürbeck, M. Fußeder F. Koch, G. Matern and A. Weghorn for their technical assistance. This work is supported by EFDA task force under contact WP09-PWI-07-03/IPP and WP10-PWI-01-04/IPP. One of authors, KS, also acknowledges the support by JSPS Postdoctoral Fellowship for research abroad.
References

[10] A. Anghel, C. Porosnicu, C. P. Lungu et al., these proceedings
[11] C. Porosnicu, A. Anghel, K. Sugiyama et al., these proceedings
Figure captions

Figure 1:
Thermal desorption spectra of D from: (a) Be and compounds (Be\(_{12}\)W and Be\(_2\)C), (b) Be and Be-W mixed deposited layers (W concentrations of ~10 % and ~60 %), (c) Be and Be-C mixed deposited layers (C concentrations of ~8 % and ~50 %), and (d) Be implanted at different temperatures (RT, 423 K and 573K). For pure Be and Be\(_2\)C samples the temperature was hold 20 min. at 623 K (see text and Fig. 2). D implantation to samples in (a),(b) and (c) was done at room temperature.

Figure 2:
Thermal desorption spectra of D from Be and Be\(_2\)C samples under the temperature programmed heating with 20 min. hold at 623 K (350 C). D implantation to those samples was done at room temperature.

Figure 3:
Remaining fraction of D in each sample as a function of temperature derived from TDS spectra of (a) Be-W system, (b) Be-C system and (c) Be implanted at different temperatures (RT, 423 K and 573 K).

Figure 4:
D remaining fraction at 623 K in Be-containing samples as a function of each impurity (W or C) concentration in Be.
Figure 1:
Thermal desorption spectra of D from: (a) Be and compounds (Be$_{12}$W and Be$_2$C), (b) Be and Be-W mixed deposited layers (W concentrations of ~10 % and ~60 %), (c) Be and Be-C mixed deposited layers (C concentrations of ~ 8 % and ~ 50 %), and (d) Be implanted at different temperatures (RT, 423 K and 573K). For pure Be and Be$_2$C samples the temperature was hold 20 min. at 623 K (see text and Fig. 2). D implantation to samples in (a),(b) and (c) was done at room temperature.
Figure 2:
Thermal desorption spectra of D from Be and Be$_2$C samples under the temperature programmed heating with 20 min. hold at 623 K (350 C). D implantation to those samples was done at room temperature.
Figure 3:
Remaining fraction of D in each sample as a function of temperature derived from TDS spectra of (a) Be-W system, (b) Be-C system and (c) Be implanted at different temperatures (RT, 423 K and 573 K).
Figure 4:
D remaining fraction at 623 K in Be-containing samples as a function of each impurity (W or C) concentration in Be.